



ALPHA & OMEGA
SEMICONDUCTOR

AO4441

60V P-Channel MOSFET

General Description

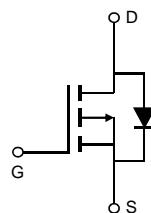
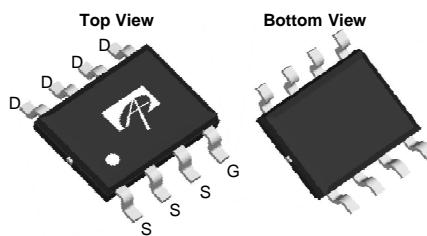
The AO4441 uses advanced trench technology to provide excellent $R_{DS(ON)}$, and ultra-low low gate charge. This device is suitable for use as a load switch or in PWM applications.

Product Summary

V_{DS}	-60V
I_D (at $V_{GS}=-10V$)	-4A
$R_{DS(ON)}$ (at $V_{GS}=-10V$)	< 100mΩ
$R_{DS(ON)}$ (at $V_{GS} = -4.5V$)	< 130mΩ



SOIC-8



Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	-60	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current ^A $T_A=25^\circ\text{C}$	I_D	-4	A
$T_A=70^\circ\text{C}$	I_D	-3.1	
Pulsed Drain Current ^B	I_{DM}	-20	
Power Dissipation ^A $T_A=25^\circ\text{C}$	P_D	3.1	W
$T_A=70^\circ\text{C}$	P_D	2	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A $t \leq 10\text{s}$	$R_{\theta JA}$	24	40	°C/W
Steady-State		54	75	°C/W
Maximum Junction-to-Lead ^C	$R_{\theta JL}$	21	30	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}, V_{GS}=0\text{V}$	-60			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-48\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			-1	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}= \pm 20\text{V}$			± 100	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu\text{A}$	-1	-2.1	-3	V
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=-10\text{V}, I_D=-4\text{A}$ $T_J=125^\circ\text{C}$	80	100		$\text{m}\Omega$
		$V_{GS}=-4.5\text{V}, I_D=-3\text{A}$	130		130	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=-5\text{V}, I_D=-4\text{A}$	10			S
V_{SD}	Diode Forward Voltage	$I_S=-1\text{A}, V_{GS}=0\text{V}$	-0.77	-1		V
I_S	Maximum Body-Diode Continuous Current				-4	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-30\text{V}, f=1\text{MHz}$		930	1120	pF
C_{oss}	Output Capacitance		85			pF
C_{rss}	Reverse Transfer Capacitance		35			pF
R_g	Gate resistance	f=1MHz	7.2	9		Ω
SWITCHING PARAMETERS						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=-10\text{V}, V_{DS}=-30\text{V}, I_D=-4\text{A}$		16	20	nC
$Q_g(4.5\text{V})$	Total Gate Charge		8	10		nC
Q_{gs}	Gate Source Charge		2.5			nC
Q_{gd}	Gate Drain Charge		3.2			nC
$t_{\text{D(on)}}$	Turn-On Delay Time	$V_{GS}=-10\text{V}, V_{DS}=-30\text{V}, R_L=7.5\Omega, R_{\text{GEN}}=3\Omega$	8			ns
t_r	Turn-On Rise Time		3.8			ns
$t_{\text{D(off)}}$	Turn-Off Delay Time		31.5			ns
t_f	Turn-Off Fall Time		7.5			ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=-4\text{A}, dI/dt=100\text{A}/\mu\text{s}$	27	35		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=-4\text{A}, dI/dt=100\text{A}/\mu\text{s}$	32			nC

A: The value of R_{JJA} is measured with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The value in any given application depends on the user's specific board design. The current rating is based on the $t \leq 10\text{s}$ thermal resistance rating.

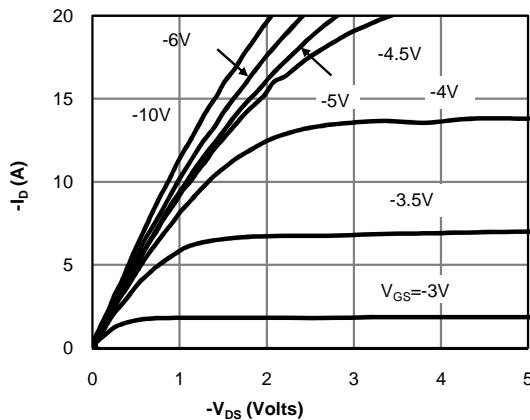
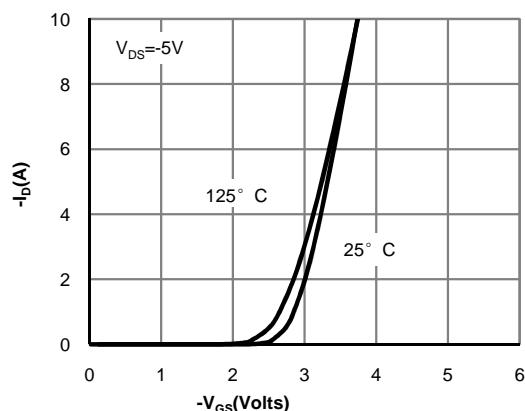
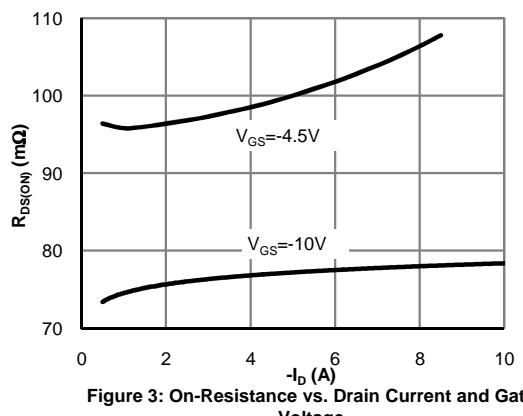
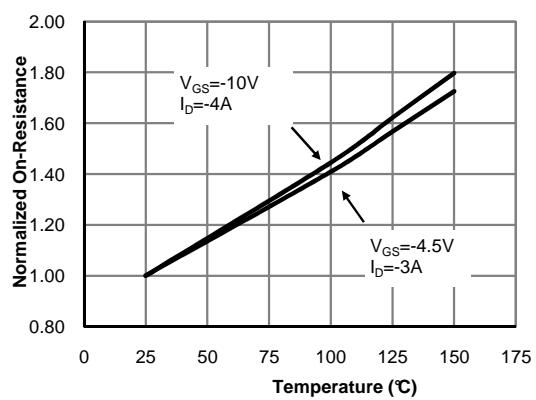
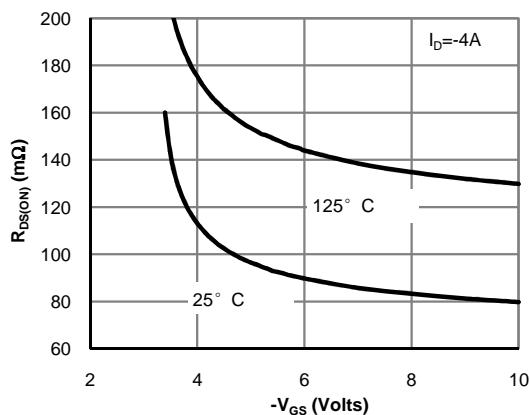
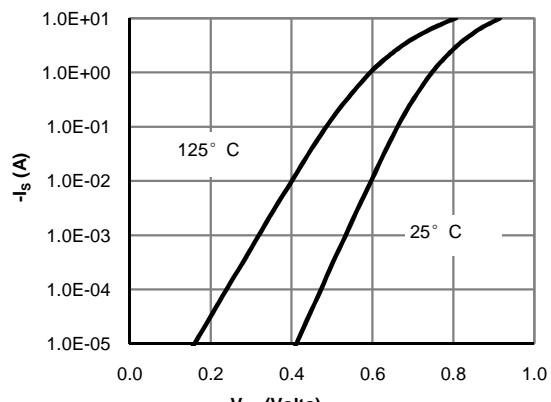
B: Repetitive rating, pulse width limited by junction temperature.

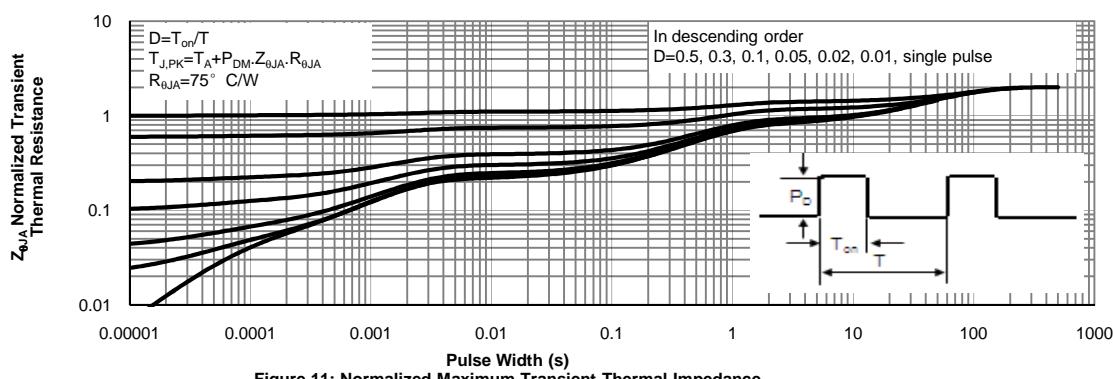
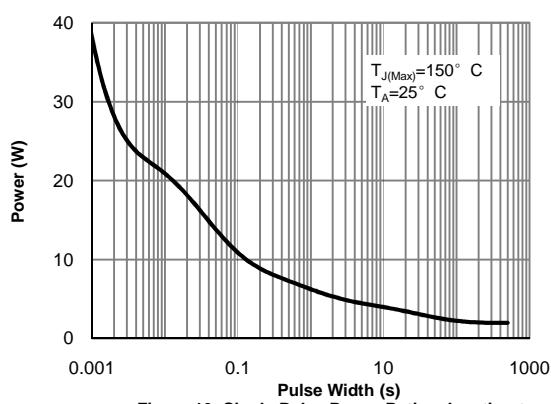
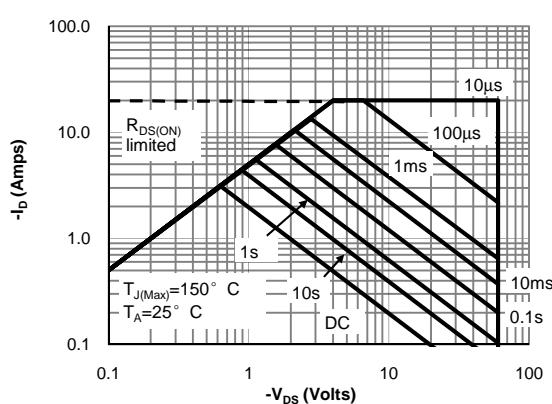
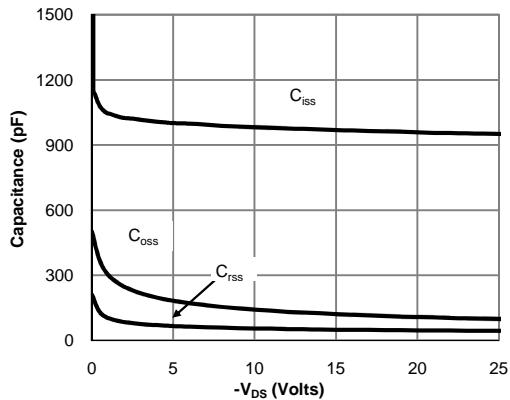
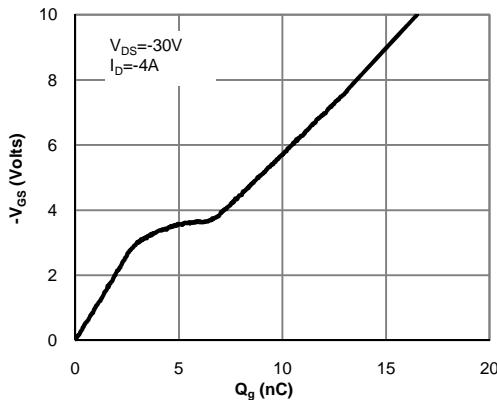
C: The R_{JJA} is the sum of the thermal impedance from junction to lead R_{JUL} and lead to ambient.

D: The static characteristics in Figures 1 to 6, 12, 14 are obtained using 80 μs pulses, duty cycle 0.5% max.

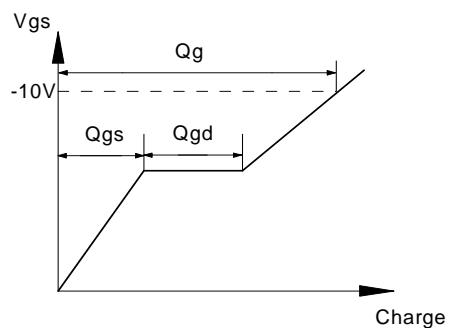
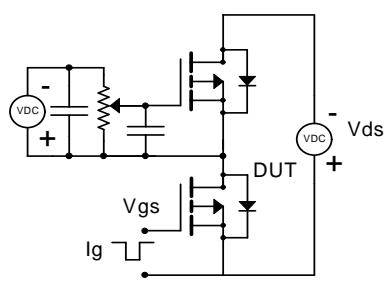
E: These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The SOA curve provides a single pulse rating.

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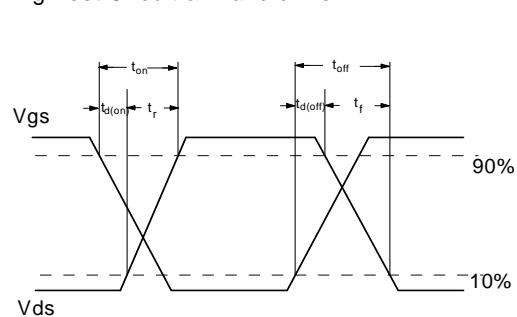
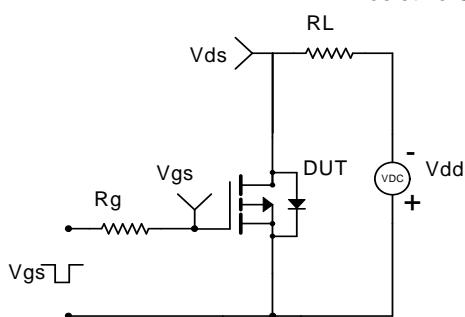
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Fig 1: On-Region Characteristics

Figure 2: Transfer Characteristics

Figure 3: On-Resistance vs. Drain Current and Gate Voltage

Figure 4: On-Resistance vs. Junction Temperature

Figure 5: On-Resistance vs. Gate-Source Voltage

Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


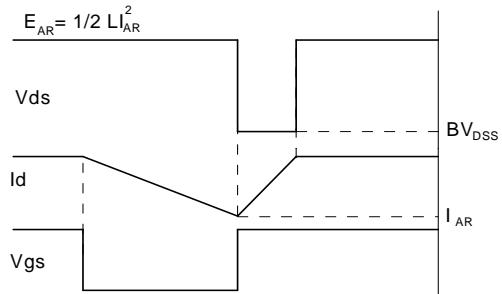
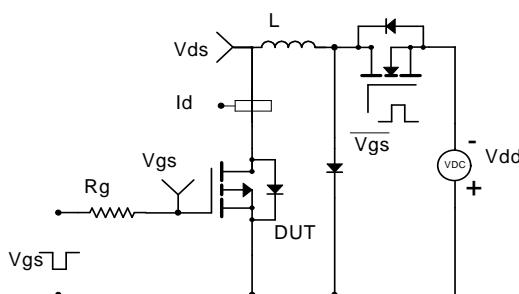
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

